

10091226  
10/09/2002  
02/28/02

PATENT NUMBER and  
ISSUE DATE

U.S. UTILITY Patent Application

10091226

APPL NUM 10091226	FILING DATE 02/28/2002	CLASS 073 433	SURCLASS 105	GAU 2812	EXAMINER Raeu's
----------------------	---------------------------	---------------------	-----------------	-------------	--------------------

\*\*APPLICANTS: Vandervorst Wilfried; Eyben Pierre;

\*\*CONTINUING DATA VERIFIED:

THIS APPLN CLAIMS BENEFIT OF 60/272,249 02/28/2001

\*\* FOREIGN APPLICATIONS VERIFIED:

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>
Foreign priority claimed <input type="checkbox"/> yes <input checked="" type="checkbox"/> no 35 USC 119 conditions met <input type="checkbox"/> yes <input checked="" type="checkbox"/> no Verified and Acknowledged Examiners's initials <i>RR</i>		ATTORNEY DOCKET NO IMEC239.001AUS
TITLE : Method and apparatus for performing atomic force microscopy measurements		

U.S. DEPT. OF COMM./PAT. & TM.-PTO-435L (Rev. 12-94)

BEST AVAILABLE COPY

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	Print Claim for O.G
Assistant Examiner  Primary Examiner		DRAWING Sheets Drwg.   Figs. Drwg.   Print Fig.	
ISSUE FEE Amount Due   Date Paid		Application Examiner	
<input type="checkbox"/> TERMINAL DISCLAIMER		PREPARED FOR ISSUE WARNING: The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368, Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only.	

FILED WITH:

☐ DISK (CRF)

☐ CD-ROM  
(Attached in pocket on right inside flap)